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Case Docket No. GIVAR7.001APC
Date: March 1, 2002

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Givargizov, et al.
Appl. No. : 09/980,432
Filed : November 29, 2001
For : TIP STRUCTURES, DEVICES
ON THEIR BASIS, AND
METHODS FOR THEIR
PREPARATION
Examiner : Unknown
Group Art Unit : Unknown

I hereby certify that this correspondence and all marked
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John M. Carson, Reg. No. 34,303

TRANSMITTAL LETTER

United States Patent and Trademark Office
Arlington, VA 22202

ATTENTION: APPLICATION BRANCH

Dear Sir:

Enclosed for filing in the above-identified application are:

- (X) An Information Disclosure Statement.
- (X) A PTO Form 1449 with nineteen (19) references.
- (X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.
- (X) Return prepaid postcard.

John M. Carson
Registration No. 34,303
Attorney of Record

GIVAR7.001APC

PATENT

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INFORMATION DISCLOSURE STATEMENT

United States Patent and Trademark Office
P.O. Box 2327
Arlington, VA 22202

Dear Sir:

Enclosed is form PTO-1449 listing references that are also enclosed. This Information Disclosure Statement is being filed before the receipt of a first Office Action on the merits, and presumably no fee is required in accordance with 37 C.F.R. § 1.97(b)(3). If a first Office Action on the merits was mailed before the mailing date of this Statement, the Commissioner is authorized to charge the fee set forth in 37 C.F.R. § 1.17(p) to Deposit Account No. 11-1410.

Form PTO-1449 lists documents that are not in English. The article written by V.A. Bykov and S.A. Saunin entitled *New devices and possibilities in scanning probe microscopy* discloses a multi-lever device in which a signal from each probe is treated in a microchip that is placed on a holder. After treating the signal, it is applied to a system for controlling a variety of levers. In this operation, piezorresistive layers are used.

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The article written by V.V. Dremov and S.P. Molchanov entitled *An alternative working mode of SPM at surface investigations* discloses that at the action of the SPM in the regime of the point scanning of adhesion forces, an ability of the device to ensure a fast damping of non-resonant oscillations, to damp the lever for its subsequent interaction with solid surface under study is important. Such a property of the device, as well as a suitable design of the cantilever, can substantially (3-5 times) decrease the time of the investigation of the surface.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 3/1/02

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| FORM PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | ATTY. DOCKET NO. GIVAR7.001APC | APPLICATION NO. 09/980,432 |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY) | | APPLICANT Givargizov, et al. | |
| | | FILING DATE November 29, 2001 | GROUP Unknown |

U.S. PATENT DOCUMENTS

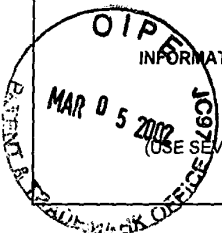
| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE (IF APPROPRIATE) |
|---------------------|-----------------|----------|--------------------|-------|----------|---------------------------------|
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FOREIGN PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|---------------------|-----------------|----------|---------|-------|----------|-------------|----|
| | | | | | | YES | NO |
| | WO 96/42101 | 12/27/96 | PCT | | | | |
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| EXAMINER INITIAL | OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.) |
|---------------------|--|
| | C.A. Spindt, et al., <i>Physical properties of thin-film field emission cathodes with molybdenum cones</i> , J. Appl. Phys., 47, pp. 5248-5263 (1976) |
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| *EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT. | |

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| FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | ATTY. DOCKET NO. GIVAR7.001APC | APPLICATION NO. 09/980,432 |
|  <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(USE SEVERAL SHEETS IF NECESSARY)</p> | APPLICANT Givargizov, et al. | |
| | FILING DATE November 29, 2001 | GROUP Unknown |

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